

Notice of References Cited	Application/Control No. 10/537,643		Applicant(s)/Patent Under Reexamination MIN ET AL.	
	Examiner Renee Danega		Art Unit 3736	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,377,845	04-2002	Kinast, Eric	600/547
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Min et al. "Design Concepts of Instruments for Vector Parameter Identification" IEEE Transactions on Instrumentation and Measurement Vol 4, February 1992, pgs 1-4.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.